

February 26-28, 2018

The Florida Hotel & Conference Center | Orlando, FL
1500 Sand Lake Road, Orlando, Florida 32809 | 1-800-588-4656

TE-13 | Tuesday, February 27 | 8:00 AM - 12:00 PM | 1/2-Day AM (4 Hours)

Course Title: Risk Based Thinking in Metrology

Instructor: Andy Oldershaw, National Research Council Canada

Track: Quality Management

Course Description:

Risk based thinking has been a growing trend spreading to all aspects of the economy and society for many years. It will become more prominent for laboratories with the adoption of the upcoming *ISO/IEC 17025* revision. This module will help those involved planning, managing, implementing and reviewing any aspect of laboratory management systems to apply risk based thinking to determine what the emphasis on risk means to their laboratory. Tools and techniques to identify, analyze, respond to, monitor and review risks will be introduced. Participants will have the opportunity to put them into practice during class room exercises.

Learning Objectives:

After this tutorial participants will be able to:

1. Identify the components of risk as they apply in metrology,
2. List common sources of measurement related risks and
3. Evaluate actions and maintain current knowledge of risks in a measurement system

After this tutorial participants will be able to apply:

1. Qualitative and quantitative risk analysis techniques for measurement related risks and
2. Apply risk based decision making in a measurement environment

Participants will be better prepared for the transition when *ISO/IEC 17025:2017* is published.